



PATENT
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Tomomi MOMOHARA

Serial No: 09/686,200 (reissue of USPN 5,818,249)

Confirmation No.: 6091

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS OF
PROBE NEEDLES IN A PROBING TEST
APPARATUS FOR TESTING
SEMICONDUCTOR INTEGRATED
CIRCUITS

Art Unit: 2829

Examiner: Nguyen, Vinh P.

I hereby certify that this correspondence
is being deposited with the United States
Postal Service with sufficient postage as
first class mail in an envelope addressed
to:

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

September 29, 2004

Date of Deposit

William H. Wright, Reg. No. 36,312

Name

Signature

Date

CHANGE OF CORRESPONDENCE ADDRESS

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Please address all future communications regarding the above-referenced patent application to:

William H. Wright
Hogan & Hartson L.L.P.
Biltmore Tower
500 South Grand Avenue, Suite 1900
Los Angeles, California 90071
Telephone: 213-337-6700
Facsimile: 213-337-6701

It is certified that the person whose signature appears below has the authority to change the correspondence address for the above-identified application.

Respectfully submitted,

HOGAN & HARTSON L.L.P.

By: 

William H. Wright

Registration No. 36,312

Attorney for Applicant(s)

Date: September 30, 2004

500 South Grand Avenue, Suite 1900
Los Angeles, California 90071
Phone: 213-337-6700
Fax: 213-337-6701